In-line Non-contact measurement module

NC-100PV

- In-line on-the-fly measurement module for solar silicon wafer
- Possible to measure Resistivity and/or Thickness by each module without contact
- Lifetime measurement module (option)
- PN type checker module (option)
- Wafer sizes : 126, 156, 210mmSQ (PSQ)
- Measurement repeatability : [Resistivity] CV≦0.5～1.0%
  [Thickness] CV≦0.5%
  (*Napson conditions)

APPLICATIONS

Silicon wafer [Mono-crystalline, Polycrystalline]

MEASURING RANGE

[Resistivity] 0.1～15Ω・cm (5～750Ω/□)
or 0.2～20Ω・cm and more
[Thickness] 100～500μm

UTILITIES

Power supply : *Select from 100～240V, 50/60Hz, 1kVA

Lifetime Measuring System for Silicon wafer

HF-300

- Non-contact, non-damage lifetime measurement by μ-PCD
- Suitable for mono-crystalline and polycrystalline silicon sample
- Passivation with exclusive capsule (for wafer sample)
- <Laser unit>
  Type : Semiconductor laser diode
  Wave length : 905nm (for wafer) / 1,000nm (for brick)
  Peak power : 60W
  Pulse width : 80nS
- Resistivity measurement [4pp or NC] (option)
- Sample sizes :
  [Wafer] <Square> ～210mm×210mmSQ
  <Circle> ～200mm
  [Brick] Max. 210(W)×500(D)×210(H)mm

APPLICATIONS

Silicon wafer, brick (bulk)
[Mono-crystalline, Polycrystalline]

MEASURING RANGE

0.1μS～1,000μS
(*Compatible to resistivity range : 0.1～1,000Ω・cm)

UTILITIES

Power supply : *Select from 100～240V, 50/60Hz, 1kVA

* Stage shutter close